

Embedded synthetic instruments for board-level testing

Jutman, Artur; Devadze, Sergei; Aleksejev, Igor; Wenzel, Thomas Proceedings : 2012 17th IEEE European Test Symposium (ETS) : May 28th–June 1st, 2012, Annecy, France 2012 / 1 p. : ill <https://ieeexplore.ieee.org/document/6233044>

FP7 collaborative research project DIAMOND : diagnosis, error modeling and correction for reliable systems design

Raik, Jaan Proceedings : 2012 17th IEEE European Test Symposium (ETS) : May 28th–June 1st, 2012, Annecy, France 2012 / 1 p <https://ieeexplore.ieee.org/document/6233052>

Re-using chip level DFT at board level

Gu, Xinli; **Jutman, Artur** Proceedings : 2012 17th IEEE European Test Symposium (ETS) : May 28th–June 1st, 2012, Annecy, France 2012 / 1 p https://www.academia.edu/25351525/Re_using_chip_level_DFT_at_board_level